Dual 2-to-4 Decoder/ Demultiplexer

MC74VHCT139A

The MC74VHCT139A is an advanced high speed CMOS 2−to−4 decoder/demultiplexer fabricated with silicon gate CMOS technology. It achieves high speed operation similar to equivalent Bipolar Schottky TTL devices while maintaining CMOS low power dissipation.

When the device is enabled ($\overline{E}$ = low), it can be used for gating or as a data input for demultiplexing operations. When the enable input is held high, all four outputs are fixed high, independent of other inputs.

The internal circuit is composed of three stages, including a buffer output which provides high noise immunity and stable output.

The device output is compatible with TTL−type input thresholds and the output has a full 5.0 V CMOS level output swing. The input protection circuitry on this device allows overvoltage tolerance on the input, allowing the device to be used as a logic−level translator from 3.0 V CMOS logic to 5.0 V CMOS logic, or from 1.8 V CMOS logic to 3.0 V CMOS logic while operating at the high−voltage power supply

The MC74VHCT139A input structure provides protection when voltages up to 7.0 V are applied, regardless of the supply voltage. This allows the MC74VHCT139A to be used to interface 5.0 V circuits to 3.0 V circuits. The output structures also provide protection when V_{CC} = 0 V. These input and output structures help prevent device destruction caused by supply voltage−input/output voltage mismatch, battery backup, hot insertion, etc.

Features

- High Speed: t_{PD} = 5.0 ns (Typ) at V_{CC} = 5.0 V
- Low Power Dissipation: I_{CC} = 4 μA (Max) at T_A = 25°C
- TTL−Compatible Inputs: V_{IL} = 0.8 V; V_{IH} = 2.0 V
- Power Down Protection Provided on Inputs and Outputs
- Balanced Propagation Delays
- Designed for 2.0 V to 5.5 V Operating Range
- Low Noise: V_{OLP} = 0.8 V (Max)
- Pin and Function Compatible with Other Standard Logic Families
- Latchup Performance Exceeds 300 mA
- ESD Performance:
  Human Body Model > 2000 V;
  Machine Model > 200 V
- Chip Complexity: 100 FETs or 25 Equivalent Gates
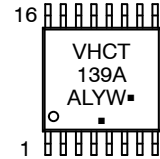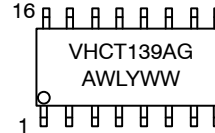- These Devices are Pb−Free and are RoHS Compliant
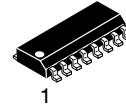
SOIC−16
D SUFFIX
CASE 751B
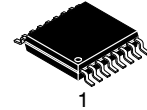
TSSOP−16
DT SUFFIX
CASE 948F

MARKING DIAGRAM

VHCT139AG
AWLYWW

VHCT
139A
ALYW▪

A	= Assembly Location
WL, L	= Wafer Lot
Y	= Year
WW, W	= Work Week
G or ▪	= Pb−Free Package

(Note: Microdot may be in either location)

FUNCTION TABLE

Inputs			Outputs			
$\overline{E}$	A1	A0	$\overline{Y0}$	$\overline{Y1}$	$\overline{Y2}$	$\overline{Y3}$
H	X	X	H	H	H	H
L	L	L	L	H	H	H
L	L	H	H	L	H	H
L	H	L	H	H	L	H
L	H	H	H	H	H	L

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.
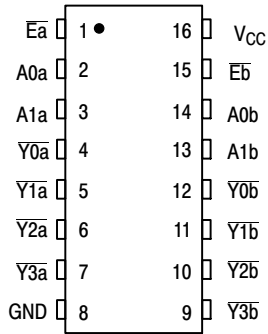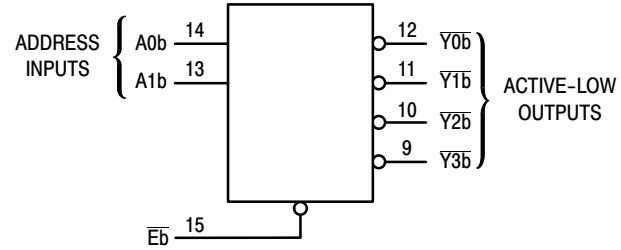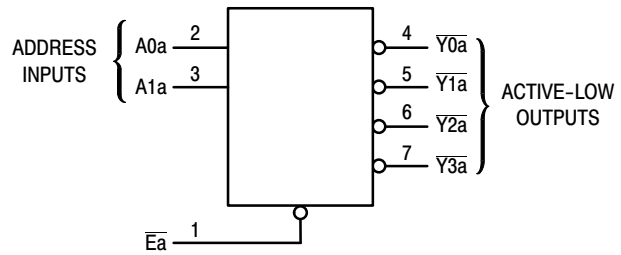
MC74VHCT139A

Figure 1. Pin Assignment

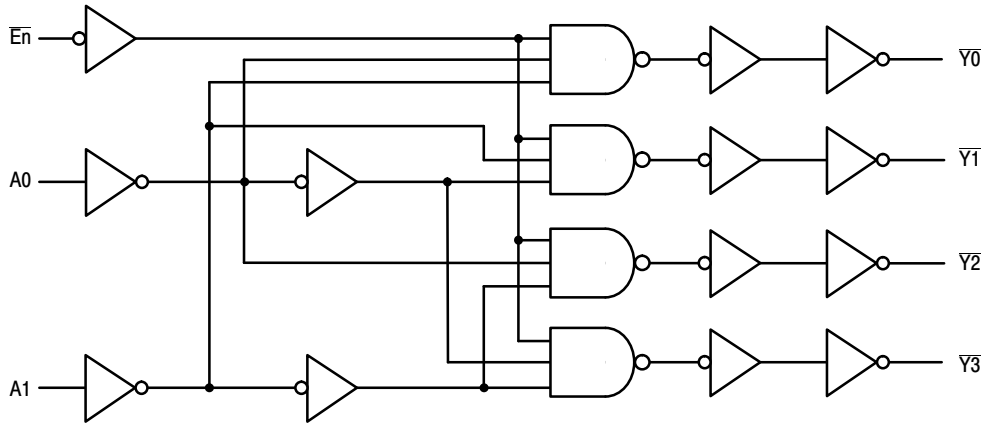**Figure 2. Logic Diagram**

Figure 3. Expanded Logic Diagram
(1/2 of Device)
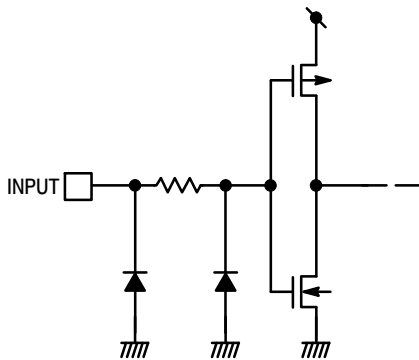

Figure 4. Input Equivalent Circuit
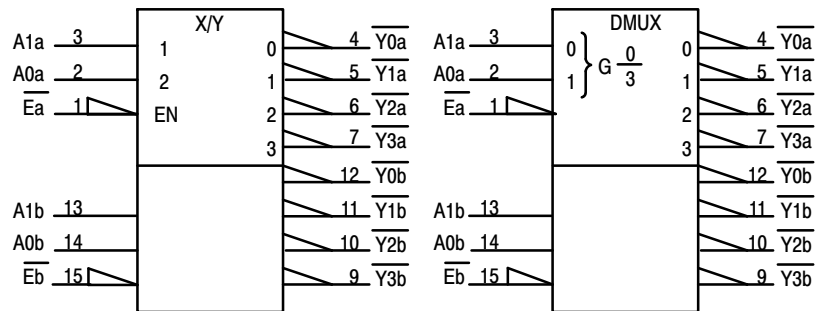
Figure 5. IEC Logic Diagram

MAXIMUM RATINGS

Symbol	Parameter		Value	Unit
V_{CC}	Positive DC Supply Voltage		−0.5 to +7.0	V
V_{IN}	Digital Input Voltage		−0.5 to +7.0	V
V_{OUT}	DC Output Voltage	Output in 3−State High or Low State	−0.5 to +7.0 −0.5 to V_{CC} +0.5	V
I_{IK}	Input Diode Current		−20	mA
I_{OK}	Output Diode Current		±20	mA
I_{OUT}	DC Output Current, per Pin		±25	mA
I_{CC}	DC Supply Current, V_{CC} and GND Pins		±75	mA
P_D	Power Dissipation in Still Air	SOIC TSSOP	200 180	mW
T_{STG}	Storage Temperature Range		−65 to +150	°C
V_{ESD}	ESD Withstand Voltage	Human Body Model (Note 1) Machine Model (Note 2) Charged Device Model (Note 3)	>2000 >200 >2000	V
$I_{LATCHUP}$	Latchup Performance	Above V_{CC} and Below GND at 125°C (Note 4)	±300	mA
θ_{JA}	Thermal Resistance, Junction−to−Ambient	SOIC TSSOP	143 164	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. Tested to EIA/JESD22−A114−A
2. Tested to EIA/JESD22−A115−A
3. Tested to JESD22−C101−A
4. Tested to EIA/JESD78

RECOMMENDED OPERATING CONDITIONS

Symbol	Characteristics		Min	Max	Unit
V_{CC}	DC Supply Voltage		4.5	5.5	V
V_{IN}	DC Input Voltage		0	5.5	V
V_{OUT}	DC Output Voltage Output in 3−State High or Low State		0 0	5.5 V_{CC}	V
T_A	Operating Temperature Range, all Package Types		−55	125	°C
t_r, t_f	Input Rise or Fall Time	V_{CC} = 5.0 V $\pm$ 0.5 V	0	20	ns/V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

DEVICE JUNCTION TEMPERATURE VERSUS TIME
TO 0.1% BOND FAILURES

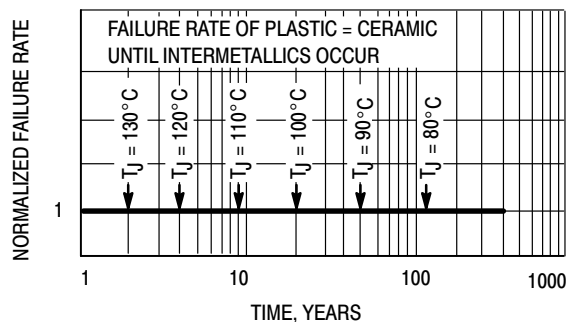| Junction Temperature °C	Time, Hours	Time, Years
80	1,032,200	117.8
90	419,300	47.9
100	178,700	20.4
110	79,600	9.4
120	37,000	4.2
130	17,800	2.0
140	8,900	1.0

Figure 6. Failure Rate vs. Time Junction Temperature

DC CHARACTERISTICS (Voltages Referenced to GND)

Symbol	Parameter	Condition	V_{CC} (V)	T_A = 25°C Min	Typ	Max	T_A ≤ 85°C Min	Max	T_A = – 55 to 125°C Min	Max	Unit
V_{IH}	Minimum High–Level Input Voltage		4.5 to 5.5	2			2		2		V
V_{IL}	Maximum Low–Level Input Voltage		4.5 to 5.5			0.8		0.8		0.8	V
V_{OH}	Maximum High–Level Output Voltage	$V_{IN} = V_{IH}$ or V_{IL} $I_{OH} = -50\ \mu A$	4.5	4.4	4.5		4.4		4.4		V
		$V_{IN} = V_{IH}$ or V_{IL} $I_{OH} = -8\ mA$	4.5	3.94			3.8		3.66		
V_{OL}	Maximum Low–Level Output Voltage	$V_{IN} = V_{IH}$ or V_{IL} $I_{OL} = 50\ \mu A$	4.5		0	0.1		0.1		0.1	V
		$V_{IN} = V_{IH}$ or V_{IL} $I_{OH} = 8\ mA$	4.5			0.36		0.44		0.52	
I_{IN}	Input Leakage Current	$V_{IN} = 5.5\ V$ or GND	0 to 5.5			±0.1		±1.0		±1.0	μA
I_{CC}	Maximum Quiescent Supply Current	$V_{IN} = V_{CC}$ or GND	5.5			4.0		40.0		40.0	μA
I_{CCT}	Additional Quiescent Supply Current (per Pin)	Any one input: $V_{IN} = 3.4\ V$ All other inputs: $V_{IN} = V_{CC}$ or GND	5.5			1.35		1.5		1.5	μA
I_{OPD}	Output Leakage Current	$V_{OUT} = 5.5\ V$	0			0.5		5		5	μA

AC ELECTRICAL CHARACTERISTICS (Input $t_r = t_f = 3.0ns$)

Symbol	Parameter	Test Conditions		T_A = 25°C Min	Typ	Max	T_A ≤ 85°C Min	Max	T_A = – 55 to 125°C Min	Max	Unit
t_{PLH}, t_{PHL}	Maximum Propagation Delay, A to Y	$V_{CC} = 3.3 \pm 0.3\ V$	$C_L = 15\ pF$ $C_L = 50\ pF$		7.2 9.7	11.0 14.5	1.0 1.0	13.0 16.5	1.0 1.0	13.0 16.5	ns
		$V_{CC} = 5.0 \pm 0.5\ V$	$C_L = 15\ pF$ $C_L = 50\ pF$		5.0 6.5	7.2 9.2	1.0 1.0	8.5 10.5	1.0 1.0	8.5 10.5	
t_{PLH}, t_{PHL}	Maximum Propagation Delay, $\overline{E}$ to Y	$V_{CC} = 3.3 \pm 0.3\ V$	$C_L = 15\ pF$ $C_L = 50\ pF$		6.4 8.9	9.2 12.7	1.0 1.0	11.0 14.5	1.0 1.0	11.0 14.5	ns
		$V_{CC} = 5.0 \pm 0.5\ V$	$C_L = 15\ pF$ $C_L = 50\ pF$		4.4 5.9	6.3 8.3	1.0 1.0	7.5 9.5	1.0 1.0	7.5 9.5	
C_{IN}	Maximum Input Capacitance				4	10		10		10	pF

		Typical @ 25°C, V_{CC} = 5.0V	
C_{PD}	Power Dissipation Capacitance (Note 5)	26	pF

5. C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation: $I_{CC(OPR)} = C_{PD} \cdot V_{CC} \cdot f_{in} + I_{CC}/2$ (per decoder). C_{PD} is used to determine the no–load dynamic power consumption; $P_D = C_{PD} \cdot V_{CC}^2 \cdot f_{in} + I_{CC} \cdot V_{CC}$.
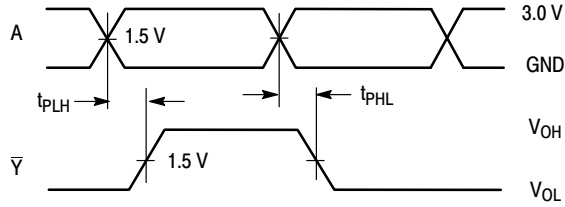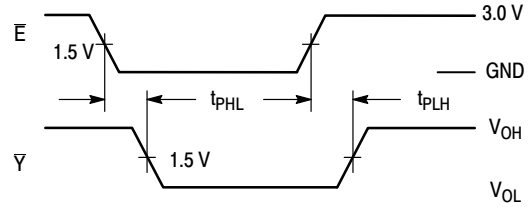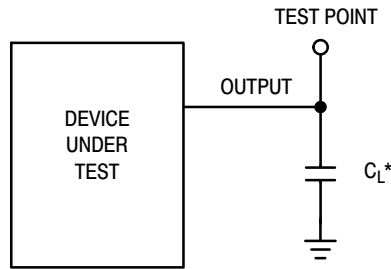
Figure 7. Switching Waveform

Figure 8. Switching Waveform

TEST POINT

OUTPUT

DEVICE UNDER TEST

C_L*

*Includes all probe and jig capacitance

Figure 9. Test Circuit

ORDERING INFORMATION

Device	Package	Shipping†
MC74VHCT139ADG	SOIC−16 (Pb−Free)	48 Units / Rail
MC74VHCT139ADR2G	SOIC−16 (Pb−Free)	2500 Tape & Reel
MC74VHCT139ADTG	TSSOP−16 (Pb−Free)	96 Units / Rail
MC74VHCT139ADTRG	TSSOP−16 (Pb−Free)	2500 Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
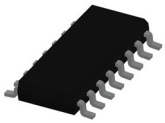
SOIC−16 9.90x3.90x1.37 1.27P
CASE 751B
ISSUE M

DATE 18 OCT 2024

NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2018.
2. DIMENSION IN MILLIMETERS. ANGLE IN DEGREES.
3. DIMENSIONS D AND E1 DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15mm PER SIDE.
5. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127mm TOTAL IN EXCESS OF THE b DIMENSION AT MAXIMUM MATERIAL CONDITION.
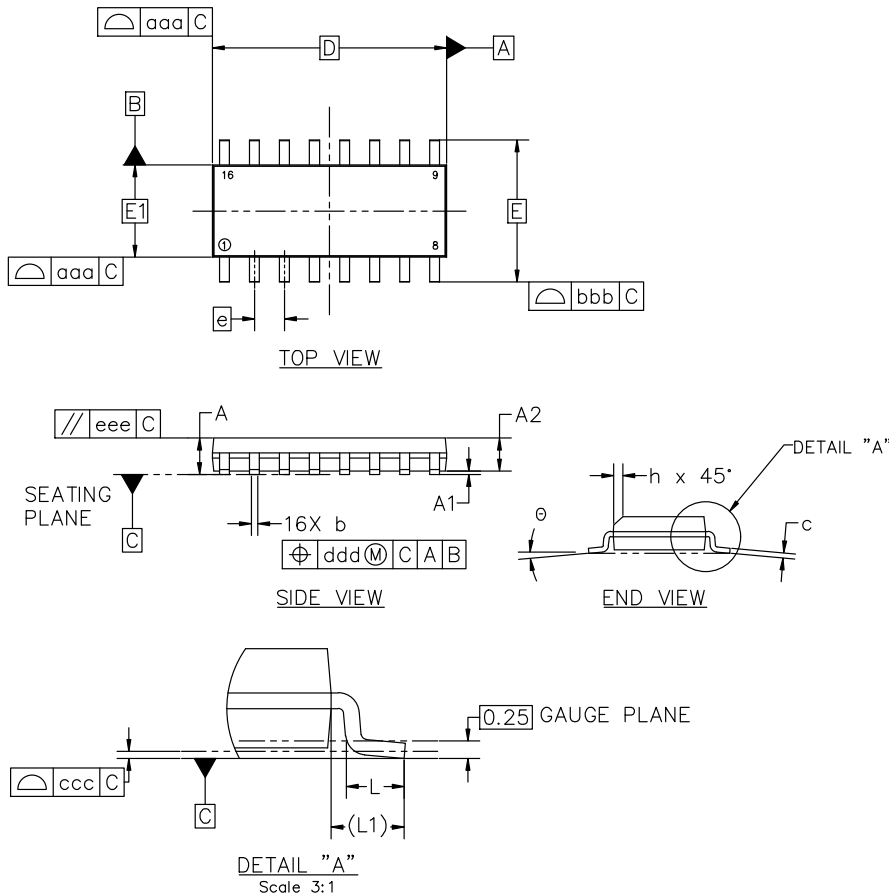
DIM	MILLIMETERS		
	MIN	NOM	MAX
A	1.35	1.55	1.75
A1	0.10	0.18	0.25
A2	1.25	1.37	1.50
b	0.35	0.42	0.49
c	0.19	0.22	0.25
D	9.90 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	1.27 BSC		
h	0.25	---	0.50
L	0.40	0.83	1.25
L1	1.05 REF		
Θ	0°	---	7°
TOLERANCE OF FORM AND POSITION			
aaa	0.10		
bbb	0.20		
ccc	0.10		
ddd	0.25		
eee	0.10		

TOP VIEW

SIDE VIEW

END VIEW

DETAIL "A"
Scale 3:1

DETAIL "A"

0.25 GAUGE PLANE

SEATING PLANE

16X b

h x 45°

8X
6.40

16X
0.58

1.270
PITCH

1.120
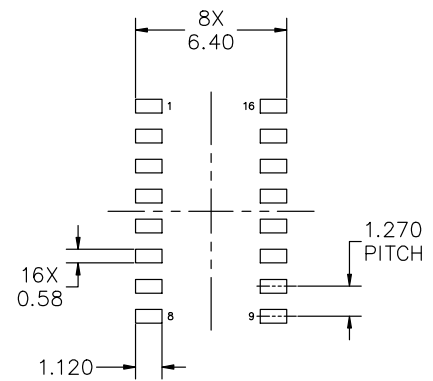
RECOMMENDED MOUNTING FOOTPRINT

*FOR ADDITIONAL INFORMATION ON OUR PB−FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE onsemi SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D
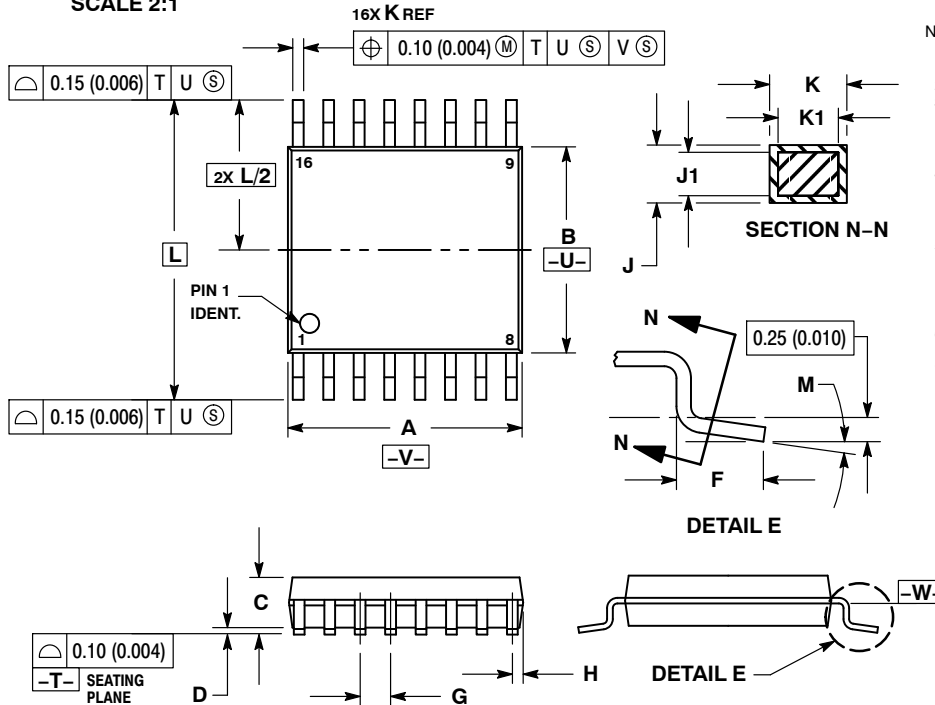
DOCUMENT NUMBER:	**98ASB42566B**	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	**SOIC−16 9.90X3.90X1.37 1.27P**		**PAGE 1 OF 2**

**GENERIC
MARKING DIAGRAM***

16 XXXXXXXXXXXXG
XXXXXXXXXXXXX
AWLYWW
1

XXXXX	= Specific Device Code
A	= Assembly Location
WL	= Wafer Lot
Y	= Year
WW	= Work Week
G	= Pb−Free Package

*This information is generic. Please refer to
device data sheet for actual part marking.
Pb−Free indicator, "G" or microdot "▪", may
or may not be present. Some products may
not follow the Generic Marking.

STYLE 1:		STYLE 2:		STYLE 3:		STYLE 4:	
PIN 1.	COLLECTOR	PIN 1.	CATHODE	PIN 1.	COLLECTOR, DYE #1	PIN 1.	COLLECTOR, DYE #1
2.	BASE	2.	ANODE	2.	BASE, #1	2.	COLLECTOR, #1
3.	EMITTER	3.	NO CONNECTION	3.	EMITTER, #1	3.	COLLECTOR, #2
4.	NO CONNECTION	4.	CATHODE	4.	COLLECTOR, #1	4.	COLLECTOR, #2
5.	EMITTER	5.	CATHODE	5.	COLLECTOR, #2	5.	COLLECTOR, #3
6.	BASE	6.	NO CONNECTION	6.	BASE, #2	6.	COLLECTOR, #3
7.	COLLECTOR	7.	ANODE	7.	EMITTER, #2	7.	COLLECTOR, #4
8.	COLLECTOR	8.	CATHODE	8.	COLLECTOR, #2	8.	COLLECTOR, #4
9.	BASE	9.	CATHODE	9.	COLLECTOR, #3	9.	BASE, #4
10.	EMITTER	10.	ANODE	10.	BASE, #3	10.	EMITTER, #4
11.	NO CONNECTION	11.	NO CONNECTION	11.	EMITTER, #3	11.	BASE, #3
12.	EMITTER	12.	CATHODE	12.	COLLECTOR, #3	12.	EMITTER, #3
13.	BASE	13.	CATHODE	13.	COLLECTOR, #4	13.	BASE, #2
14.	COLLECTOR	14.	NO CONNECTION	14.	BASE, #4	14.	EMITTER, #2
15.	EMITTER	15.	ANODE	15.	EMITTER, #4	15.	BASE, #1
16.	COLLECTOR	16.	CATHODE	16.	COLLECTOR, #4	16.	EMITTER, #1

STYLE 5:		STYLE 6:		STYLE 7:	
PIN 1.	DRAIN, DYE #1	PIN 1.	CATHODE	PIN 1.	SOURCE N-CH
2.	DRAIN, #1	2.	CATHODE	2.	COMMON DRAIN (OUTPUT)
3.	DRAIN, #2	3.	CATHODE	3.	COMMON DRAIN (OUTPUT)
4.	DRAIN, #2	4.	CATHODE	4.	GATE P-CH
5.	DRAIN, #3	5.	CATHODE	5.	COMMON DRAIN (OUTPUT)
6.	DRAIN, #3	6.	CATHODE	6.	COMMON DRAIN (OUTPUT)
7.	DRAIN, #4	7.	CATHODE	7.	COMMON DRAIN (OUTPUT)
8.	DRAIN, #4	8.	CATHODE	8.	SOURCE P-CH
9.	GATE, #4	9.	ANODE	9.	SOURCE P-CH
10.	SOURCE, #4	10.	ANODE	10.	COMMON DRAIN (OUTPUT)
11.	GATE, #3	11.	ANODE	11.	COMMON DRAIN (OUTPUT)
12.	SOURCE, #3	12.	ANODE	12.	COMMON DRAIN (OUTPUT)
13.	GATE, #2	13.	ANODE	13.	GATE N-CH
14.	SOURCE, #2	14.	ANODE	14.	COMMON DRAIN (OUTPUT)
15.	GATE, #1	15.	ANODE	15.	COMMON DRAIN (OUTPUT)
16.	SOURCE, #1	16.	ANODE	16.	SOURCE N-CH

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DESCRIPTION:	**SOIC−16 9.90X3.90X1.37 1.27P**		**PAGE 2 OF 2**

TSSOP−16 WB
CASE 948F
ISSUE B

DATE 19 OCT 2006

16

1

SCALE 2:1

16X K REF

⊕ 0.10 (0.004) Ⓜ T U Ⓢ V Ⓢ

△ 0.15 (0.006) T U Ⓢ

2X L/2

L

16   9

PIN 1
IDENT.

1   8

△ 0.15 (0.006) T U Ⓢ

A

−V−

B

−U−

K

K1

J1

J

SECTION N−N

N

0.25 (0.010)

M

N

F

DETAIL E

C

△ 0.10 (0.004)

−T− SEATING
PLANE

D   G   H

−W−

DETAIL E

NOTES:
1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSION A DOES NOT INCLUDE MOLD FLASH. PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
7. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE −W−.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.90	5.10	0.193	0.200
B	4.30	4.50	0.169	0.177
C	–––	1.20	–––	0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65 BSC		0.026 BSC	
H	0.18	0.28	0.007	0.011
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
M	0 °	8 °	0 °	8 °

**RECOMMENDED
SOLDERING FOOTPRINT***

7.06

1

0.65
PITCH

16X
0.36

16X
1.26

DIMENSIONS: MILLIMETERS

**GENERIC
MARKING DIAGRAM***

16

XXXX
XXXX
□ ALYW

1

XXXX = Specific Device Code
A   = Assembly Location
L   = Wafer Lot
Y   = Year
W   = Work Week
G or ▪ = Pb−Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb−Free indicator, "G" or microdot " ▪", may or may not be present. Some products may not follow the Generic Marking.

*For additional information on our Pb−Free strategy and soldering details, please download the **onsemi** Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	TSSOP−16		**PAGE 1 OF 1**

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:
Technical Library: www.onsemi.com/design/resources/technical-documentation
onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support
For additional information, please contact your local Sales Representative at
www.onsemi.com/support/sales

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